

ADC

ARCHITECTURES & SPECIFICATIONS

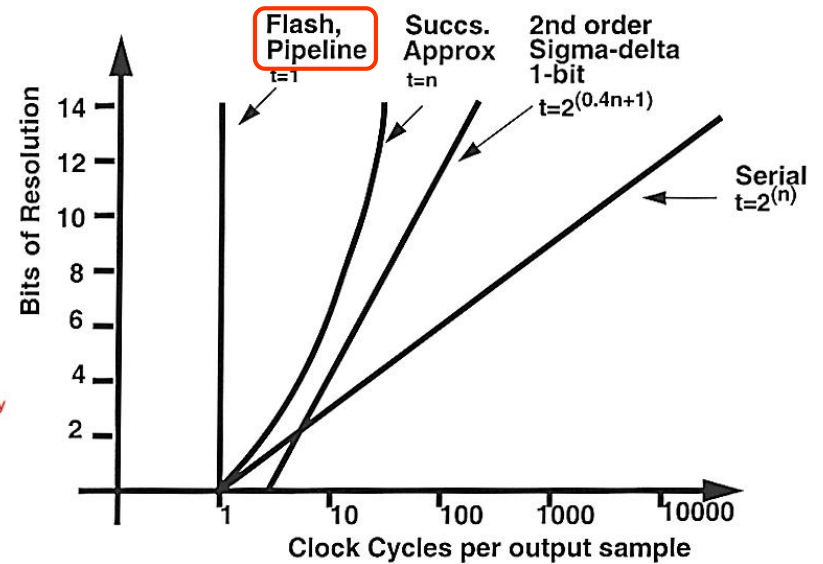
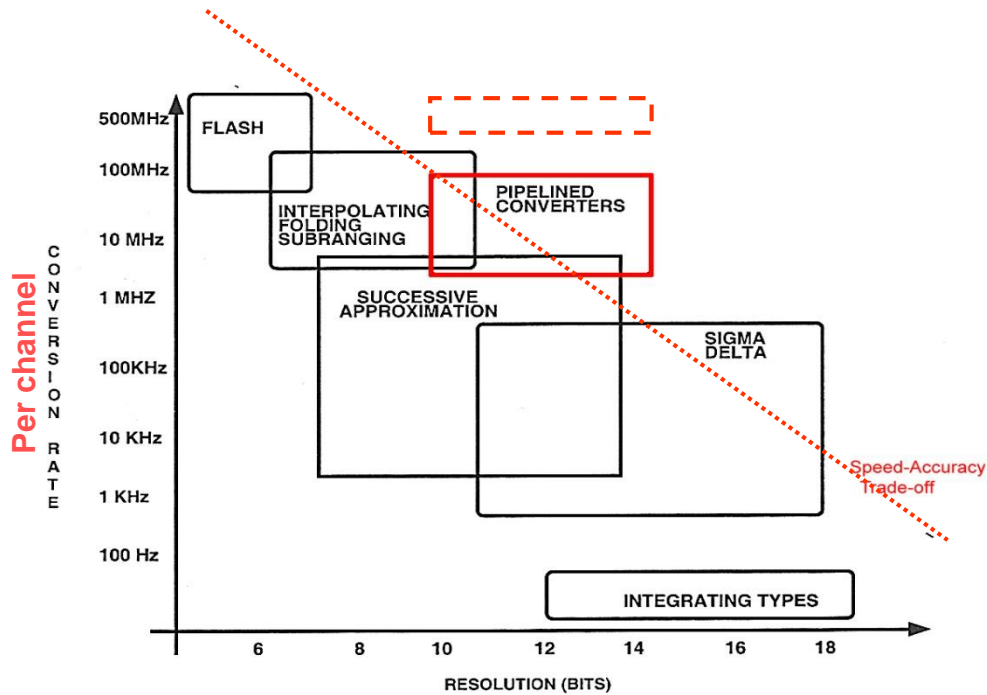
What is an ADC?

- Mixed signal circuit:
 - Analog input signal
 - Digital output signal
- ADC **discretize** the **continuous input signal** in **time** and **amplitude**
- Output Code is defined by:

$$- \sum_{i=0}^N \frac{2^i(G \cdot V_{in})}{V_{ref}}$$

- G is the gain factor, N the resolution, V_{in} the input signal and V_{ref} is the dynamic range of the converter

High speed ADC: general overview



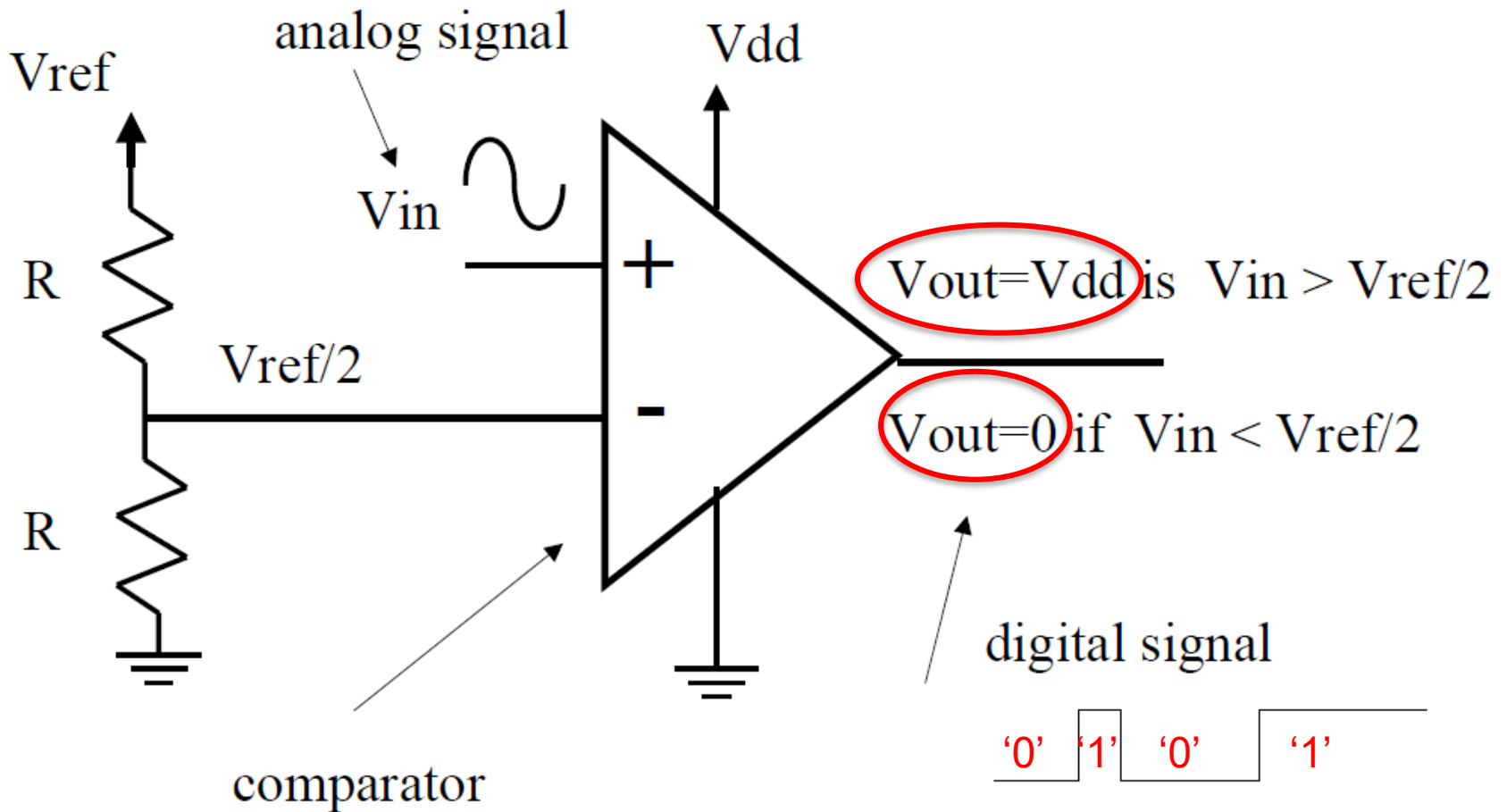
ADC architecture timeline
(source: Analog Devices)

- 1939: Counting ADC (Reeves)
- 1946: Successive approximation
- 1948: Flash (electron tube coders)
- 1956: Bit-per-stage (binary and folding-Gray)
- 1956: Sub-ranging
- 1964: Sub-ranging with error correction
- 1966: Pipe line with error correction**

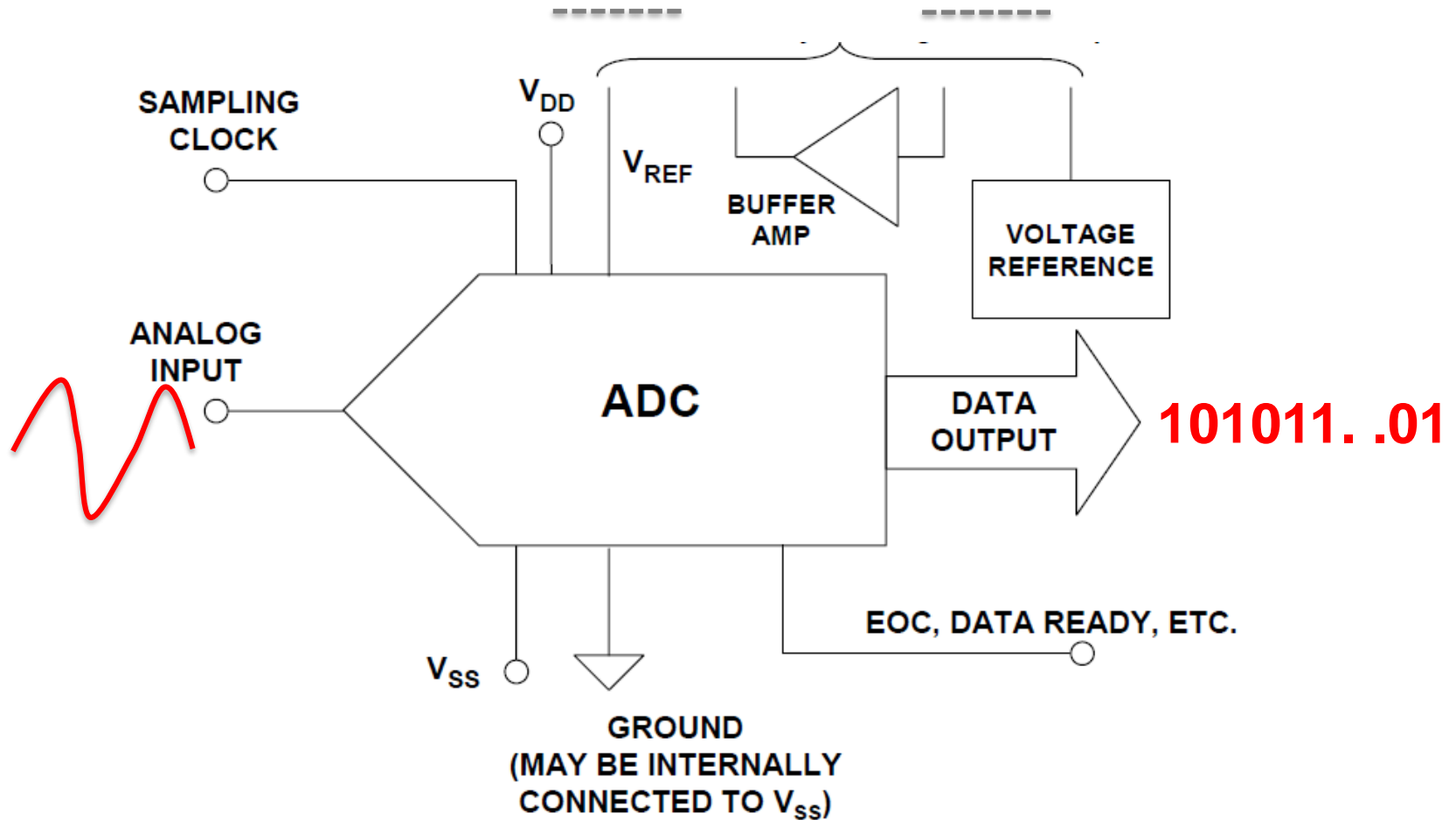
ADC Architectures

- Slope type converters
- Successive approximation
- Flash
- Time-interleaved / parallel converter
- Folding
- Residue type ADCs
 - Two-step
 - Pipeline
 - ...
- Oversampled ADCs

From Analog signal to digital code

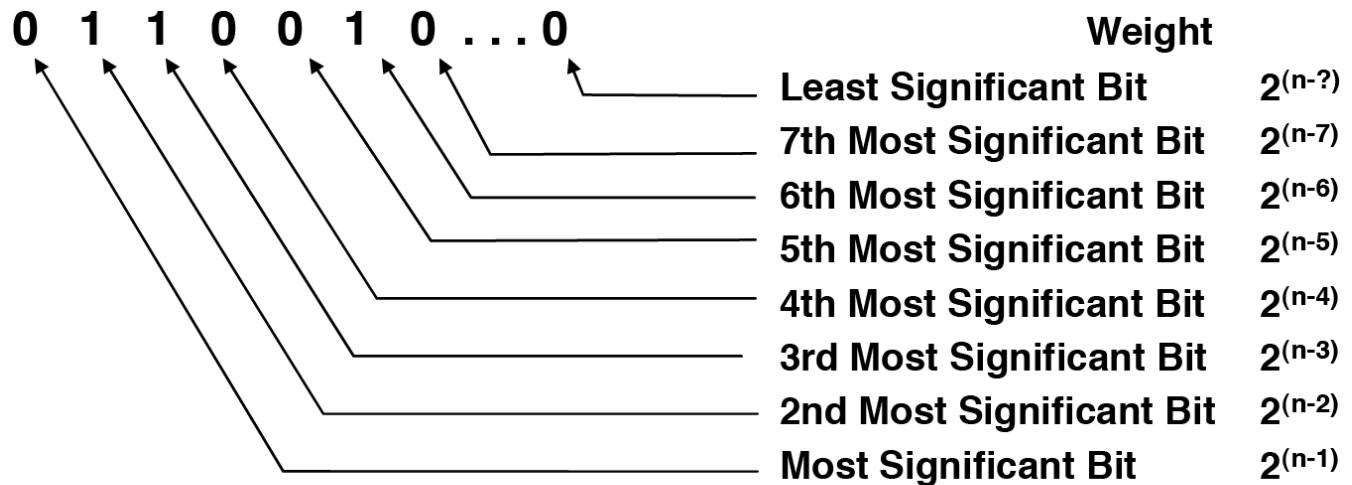


ADC input and output



definition

- **LSB:** Least Significant Bit
- **MSB:** Most Significant Bit



Bit Weights of an 8-Bit Word

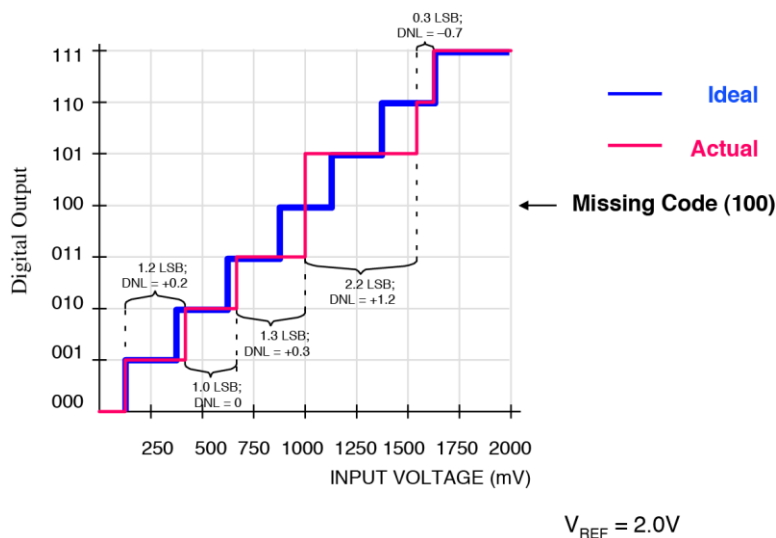
MSB								LSB
B7	B6	B5	B4	B3	B2	B1	B0	
128	64	32	16	8	4	2	1	

LSB – Resolution – V_{ref}

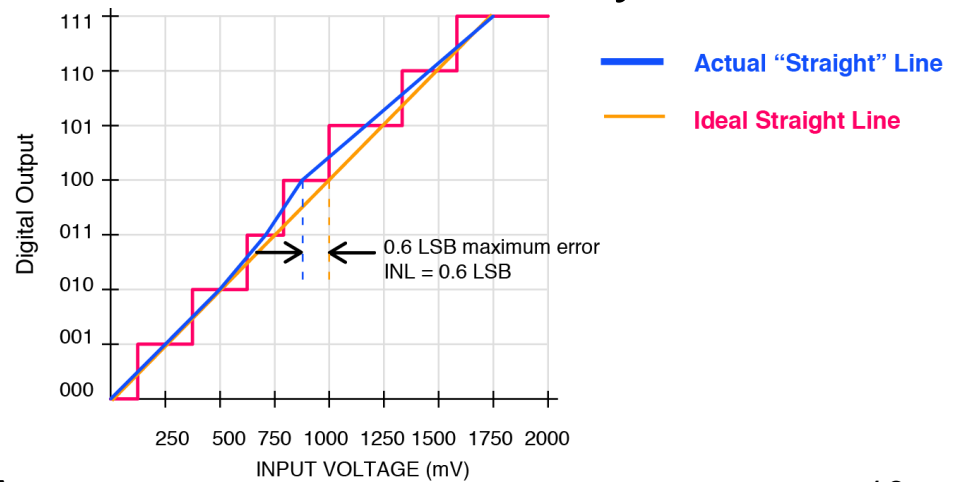
V_{REF}	Resolution	1 LSB
1.00V	8	3.9062 mV
1.00V	12	244.14 μV
2.00V	8	7.8125 mV
2.00V	10	1.9531 mV
2.00V	12	488.28 μV
2.048V	10	2.0000 mV
2.048V	12	500.00 μV
4.00V	8	15.625 mV
4.00V	10	3.9062 mV
4.00V	12	976.56 μV

Static parameters: DNL/INL

- Measure the linearity issue
 - Define how the gain can keep constant
- **DNL**: Differential Non Linearity
 - Proximity error between two successive codes
- **INL**: Integral Non Linearity
 - Deviation from a straight line on the whole dynamic



D/A



$V_{REF} = 2.0V$

ADC Parameters

- Static

- DNL
$$DNL(k) = \frac{(X_{k+1} - X_k) - \Delta}{\Delta}$$

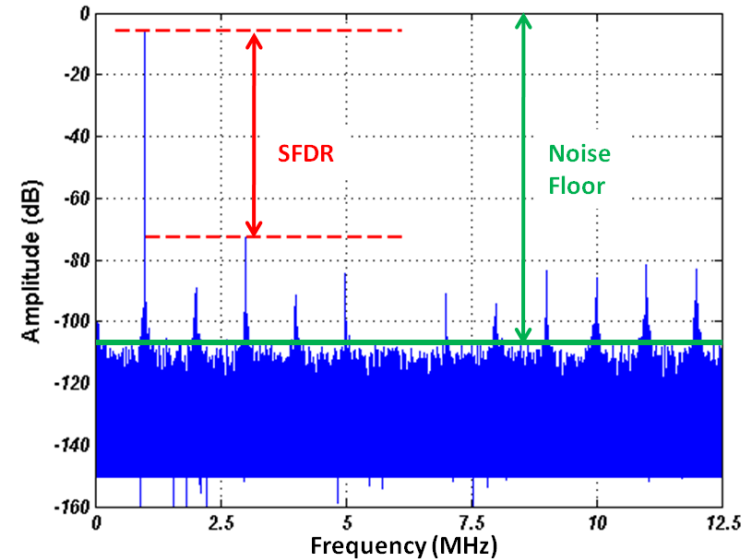
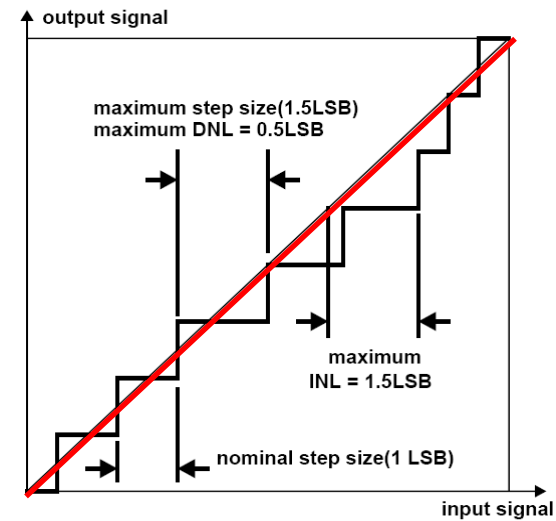
- INL
$$INL(k) = \sum_{i=0}^k DNL(i)$$

- Dynamic

$$SNR_{dB} = 10 \cdot \log_{10} \left(\frac{P_s}{P_n} \right)$$

$$SFDR_{dB} = 10 \cdot \log_{10} \left(\frac{P_s}{P_h} \right)$$

$$ENOB = \frac{SINAD_{dB} - 1.76}{6.02}$$

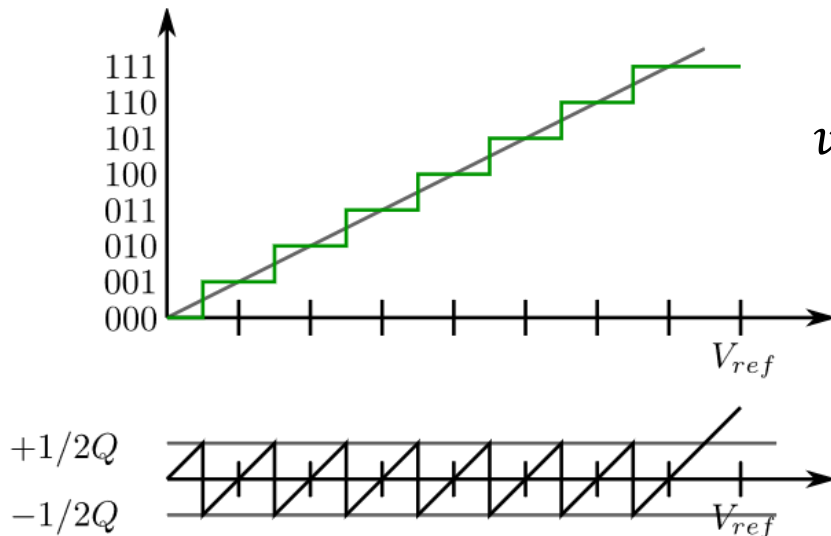


$$FoM = \frac{P}{2^{ENOB} \cdot f_s} \cdot V_{DD}$$

Quantization noise

- The fact that the input signal is *quantized* means that noise is added to it
- Quantization noise is less with higher resolution as the input range is divided into a greater number of smaller ranges
- It has a uniform distribution ranging from $-Q/2$ to $+Q/2$
- This error can be considered a quantization noise with **RMS**

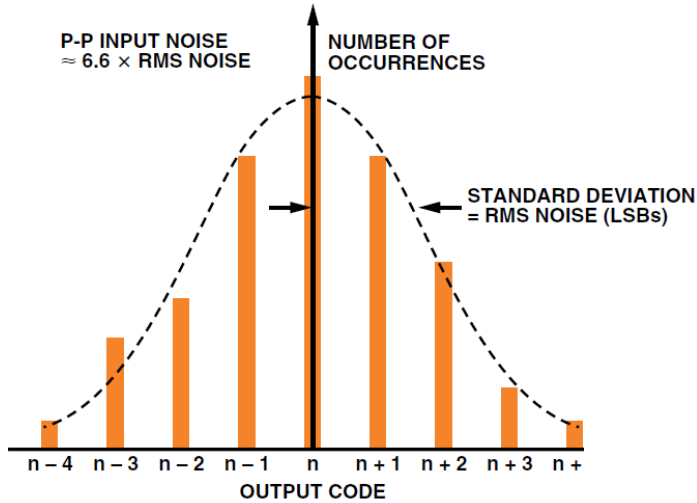
➡ Summing the energy



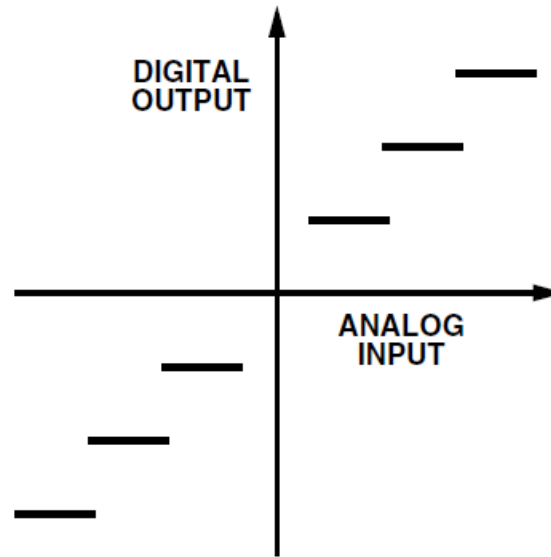
$$v_{qn} = \sqrt{\frac{1}{Q} \cdot \int_{-Q/2}^{+Q/2} x^2 dx} = \sqrt{\frac{1}{Q} \cdot \left[\frac{x^3}{3} \right]_{-Q/2}^{+Q/2}}$$

$$v_{qn} = \sqrt{\frac{Q^2}{2^3 \cdot 3} + \frac{Q^2}{2^3 \cdot 3}} = \frac{Q}{\sqrt{12}}$$

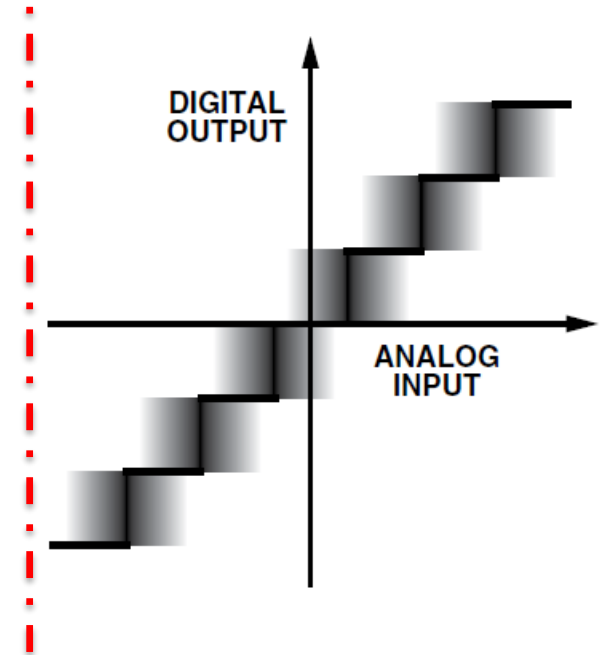
Noise issues in tranfert function



Ideal tranfert function curve

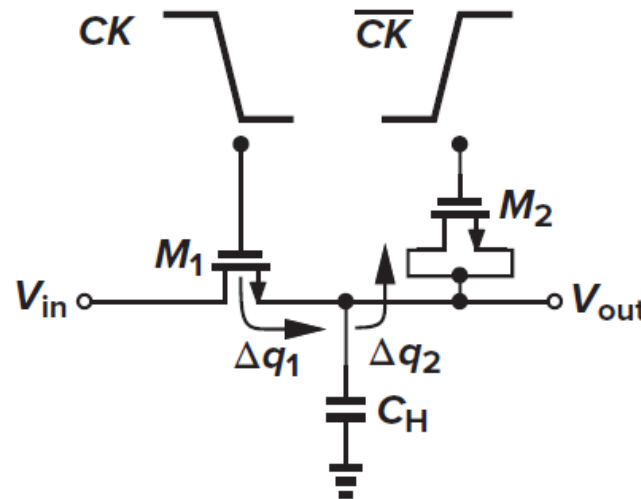


Tranfert function curve with 1LSB_{PP} transition noise



Channel Charge Injection: Compensation techniques

- We postulate that the charge injected by the main transistor M_1 can be *removed* by means of a second transistor M_2
- A “dummy” switch, M_2 , driven by \overline{CK} is added to the circuit such that after M_1 turns off and M_2 turns on, the channel charge deposited by the former on C_H is absorbed by the latter to create a channel
- Note that both the source and drain of M_2 are connected to the output node



Thermal noise KT/C

- From the switch capacitor circuit and the resistance of the switch, we can define the transfer function $\frac{V_{out}}{V_{in}}$ as:

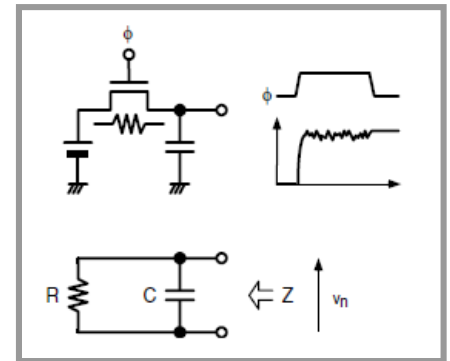
$$\frac{V_{out}}{V_{in}} = \frac{1}{1 + RCp}$$

- PSD Noise from **resistance** is defined by:

$$S_v(f) = 4kTR$$

- The Output PSD Noise is then:

$$S_{out}(f) = 4kTR \left| \frac{V_{out}}{V_{in}} \right|^2$$



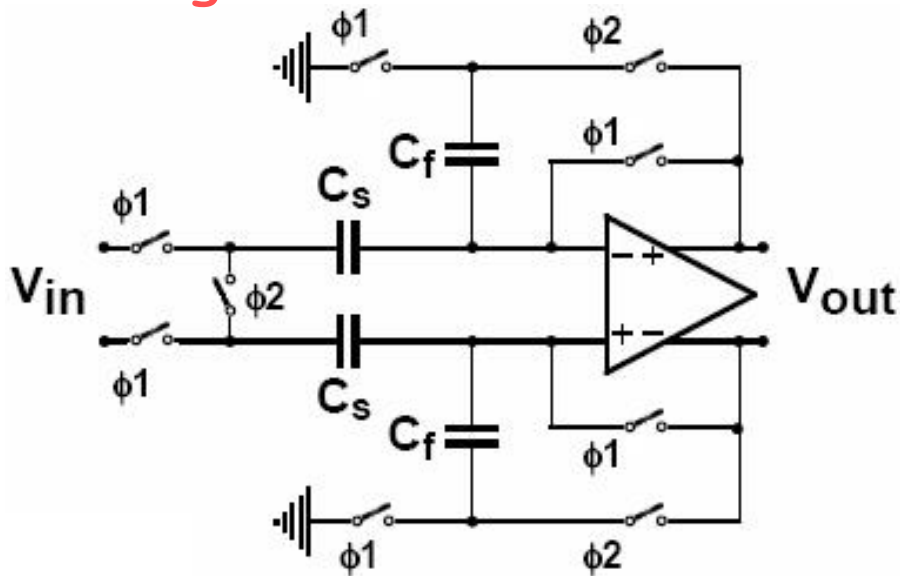
- The white noise spectrum of the resistor is shaped by a low-pass characteristic, and the the total noise power at the output is:

$$P_{n,out} = \int_0^{\infty} \frac{4kTR}{4\pi^2 R^2 C^2 f^2 + 1} df = \frac{kT}{C} \int_{-a}^a \frac{dx}{1+x^2} = 2 \arctan a$$

- This noise is a function only of temperature and capacitance values

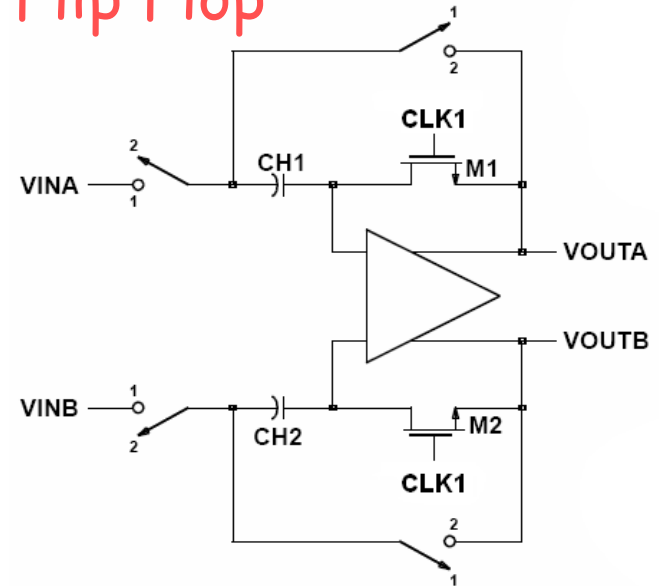
THE Track "Sample" and Hold

Charge redistribution



- + single ended to differential
- + less sensitive to CM error
- + Offset cancelled (differentially)
- Noise (a factor $\sqrt{2}$ more)
- Gain mismatch

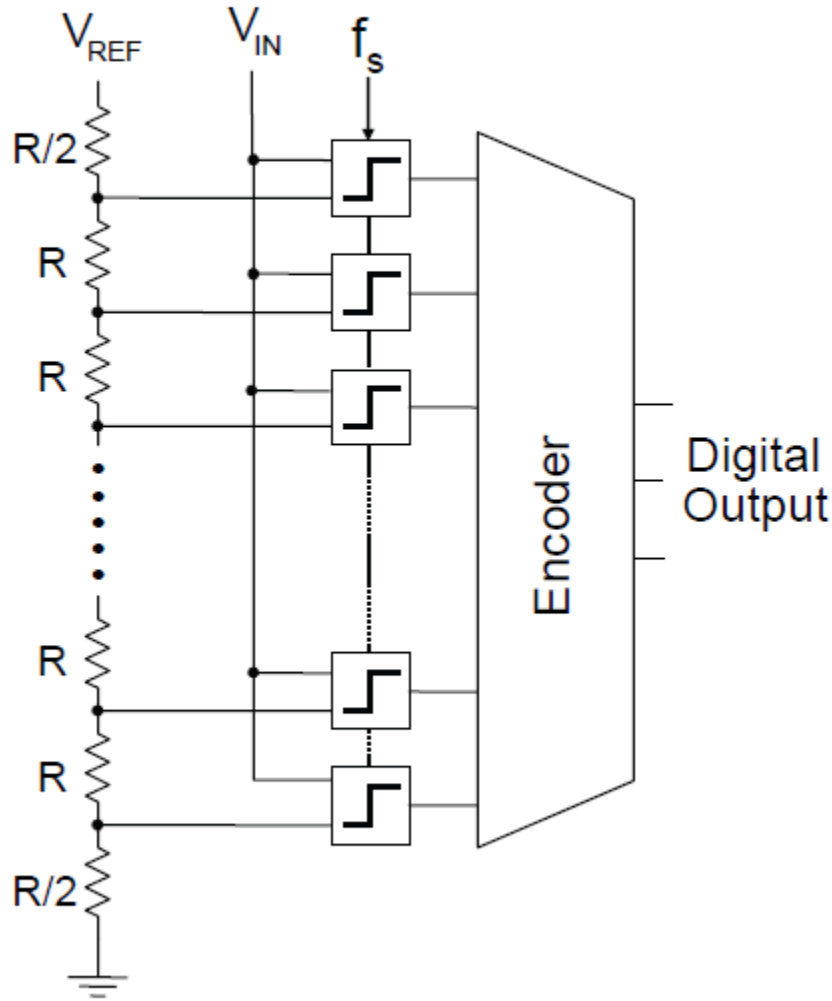
Flip Flop



- + Mismatch insensitive; gain=1
- + Less noise
- + Offset cancelled (differentially)
- Sensitive to CM fluctuations
- Need full differential inputs

ADC ARCHITECTURES

Flash Converter Sources of Error



- Comparator input:
 - Offset
 - Nonlinear input capacitance
 - Kickback noise (disturbs reference)
 - Signal dependent sampling time
- Comparator output:
 - Sparkle codes (... 111101000 ...)
 - Metastability

Pros & Cons about Flash ADC

Flash is fast,

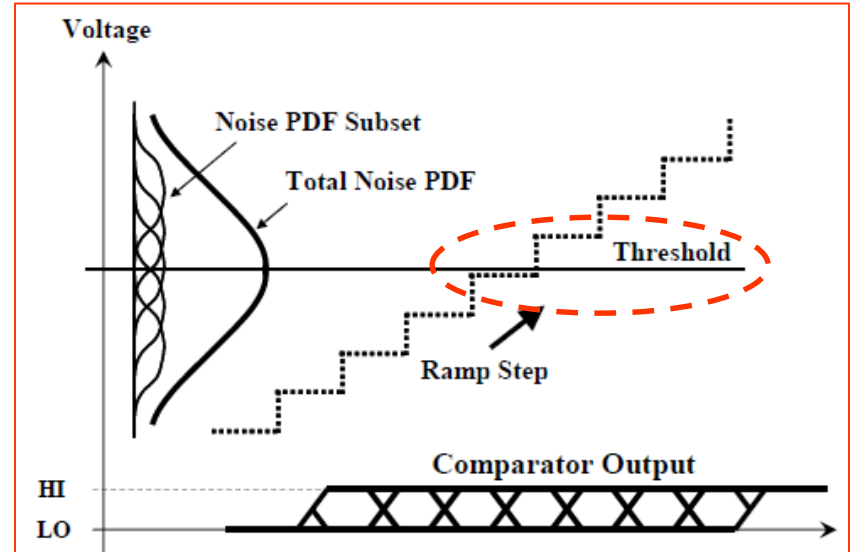
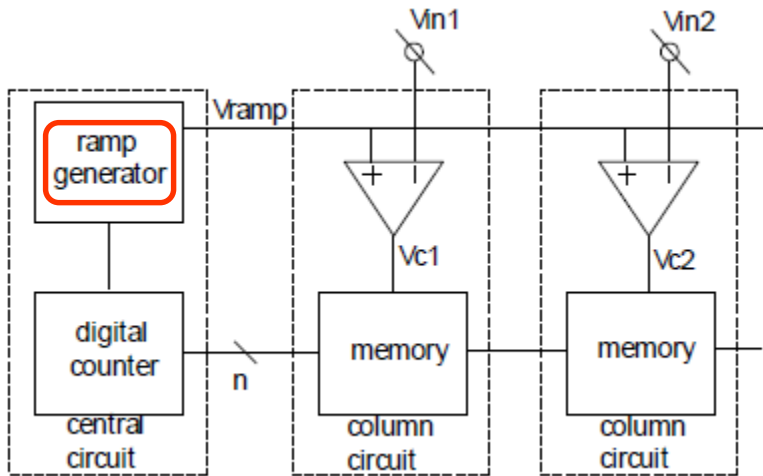
$2^b - 1$ comparators simultaneously sample the input signal

But, for high resolution,

Number of comparators increases exponentially with b

- very large ICs, high power dissipation, difficulty in matching components, and, the increasingly large input capacitance reduces analog input bandwidth
- currently available, $b \leq 8$

Rampe ADC



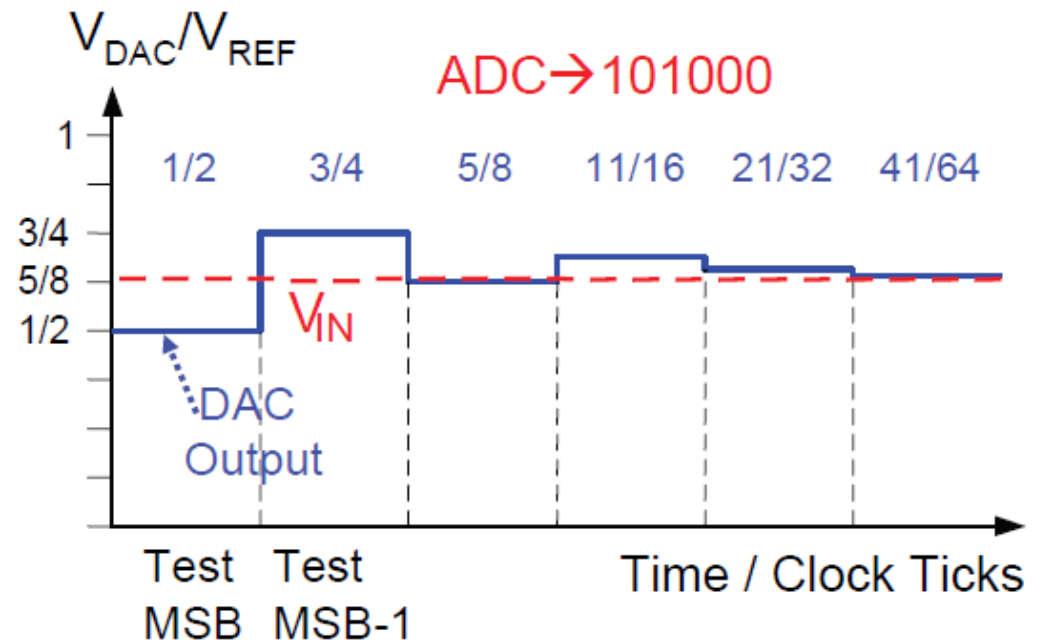
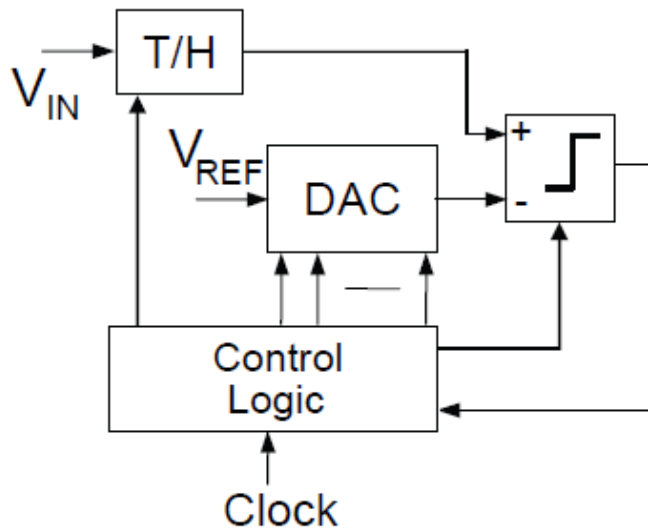
Widely used for CIS:

-inherently simple, scalable to small pitch

However: slow, sensitive to the noise of the common ramp driver and comparator, and the clock jitter while close to the threshold voltage and the noise estimator.

Successive Approximation ADC

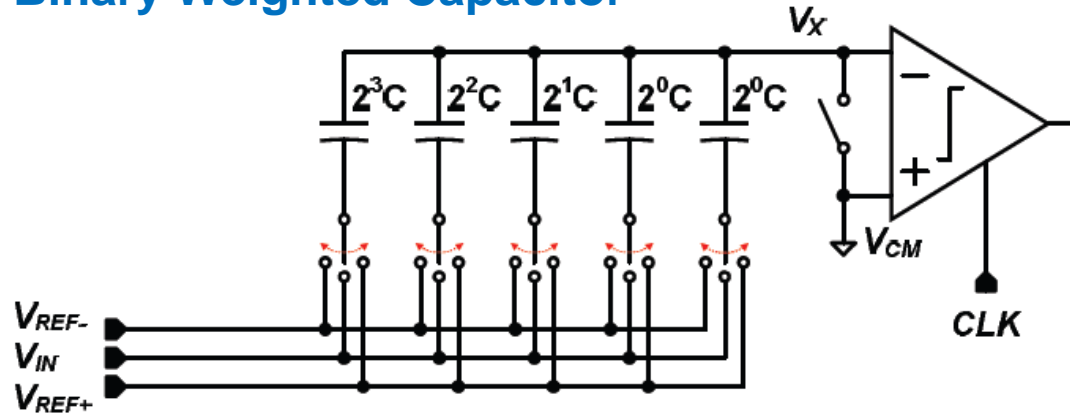
Example: 6-bit ADC & $V_{IN} = 5/8 V_{REF}$



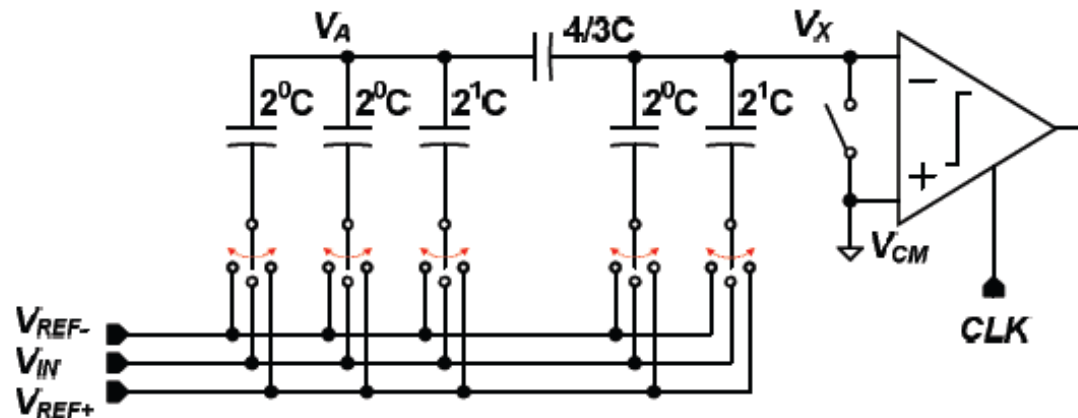
- High accuracy achievable (16+ Bits)
- Required N clock cycles for N-bit conversion (much faster than slope type)

Low power SAR \Rightarrow ADC with sampling capacitors

Binary Weighted Capacitor

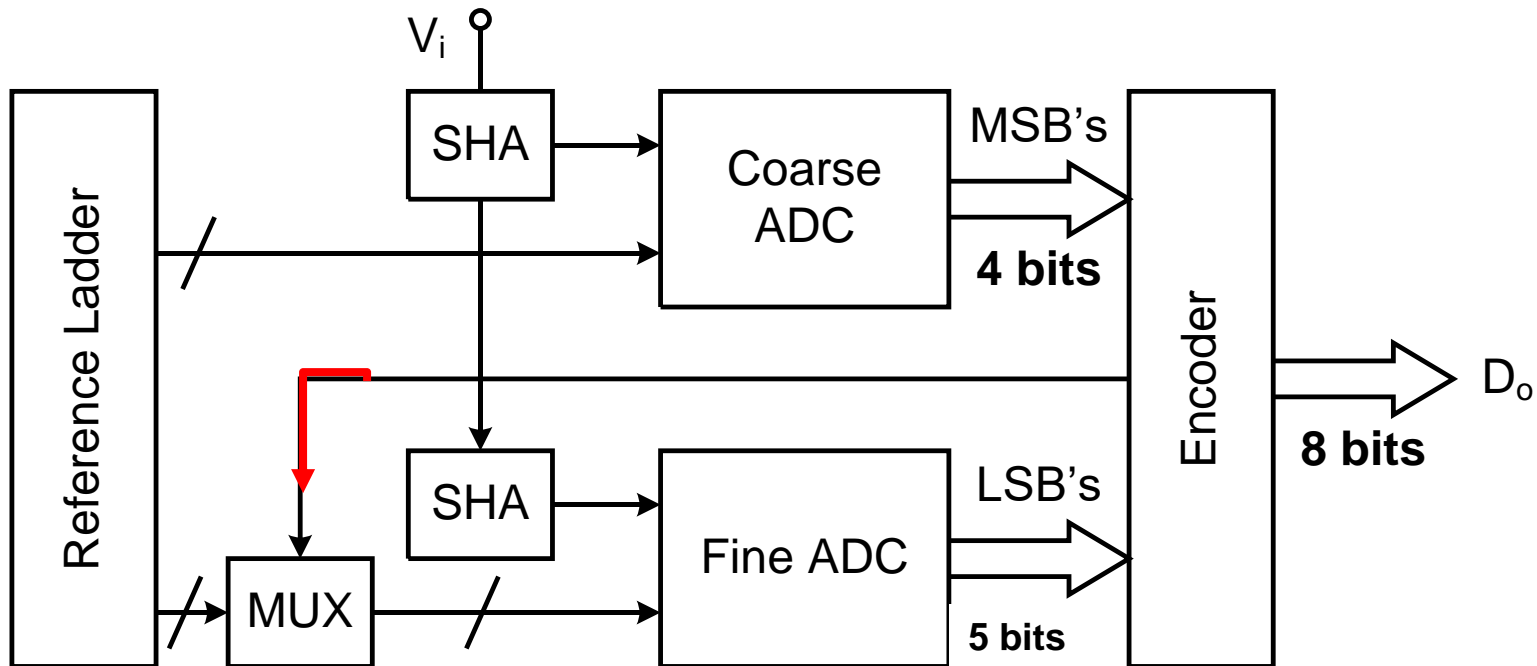


Segmented-Binary Weighted Capacitors



Sub-ranging ADC

Sub-ranging ADC also **doesn't require OpAmp** and suitable for LV operation. However it requires **high accuracy devices** , for the “fine ADC”.

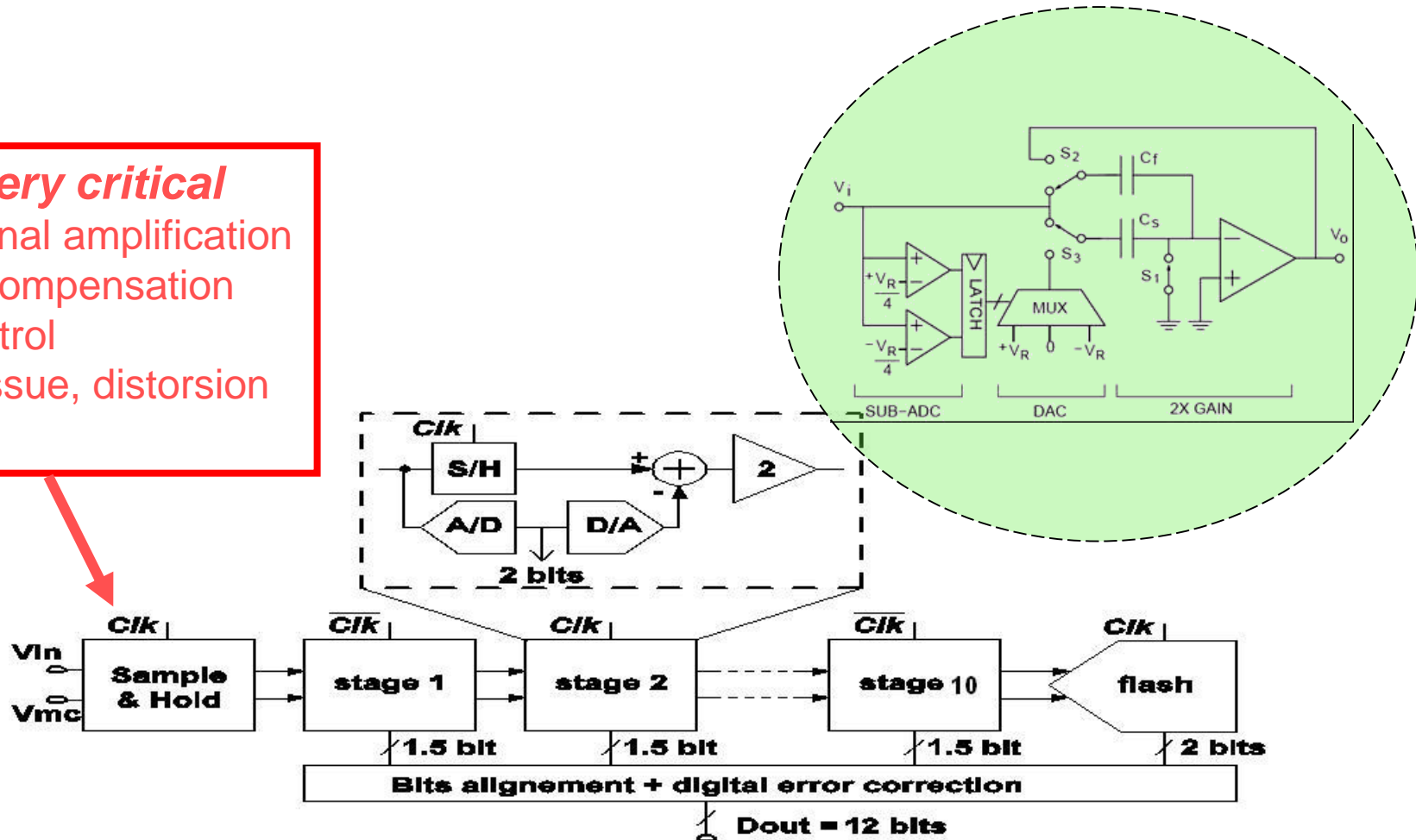


Pipe line ADC design: the baseline

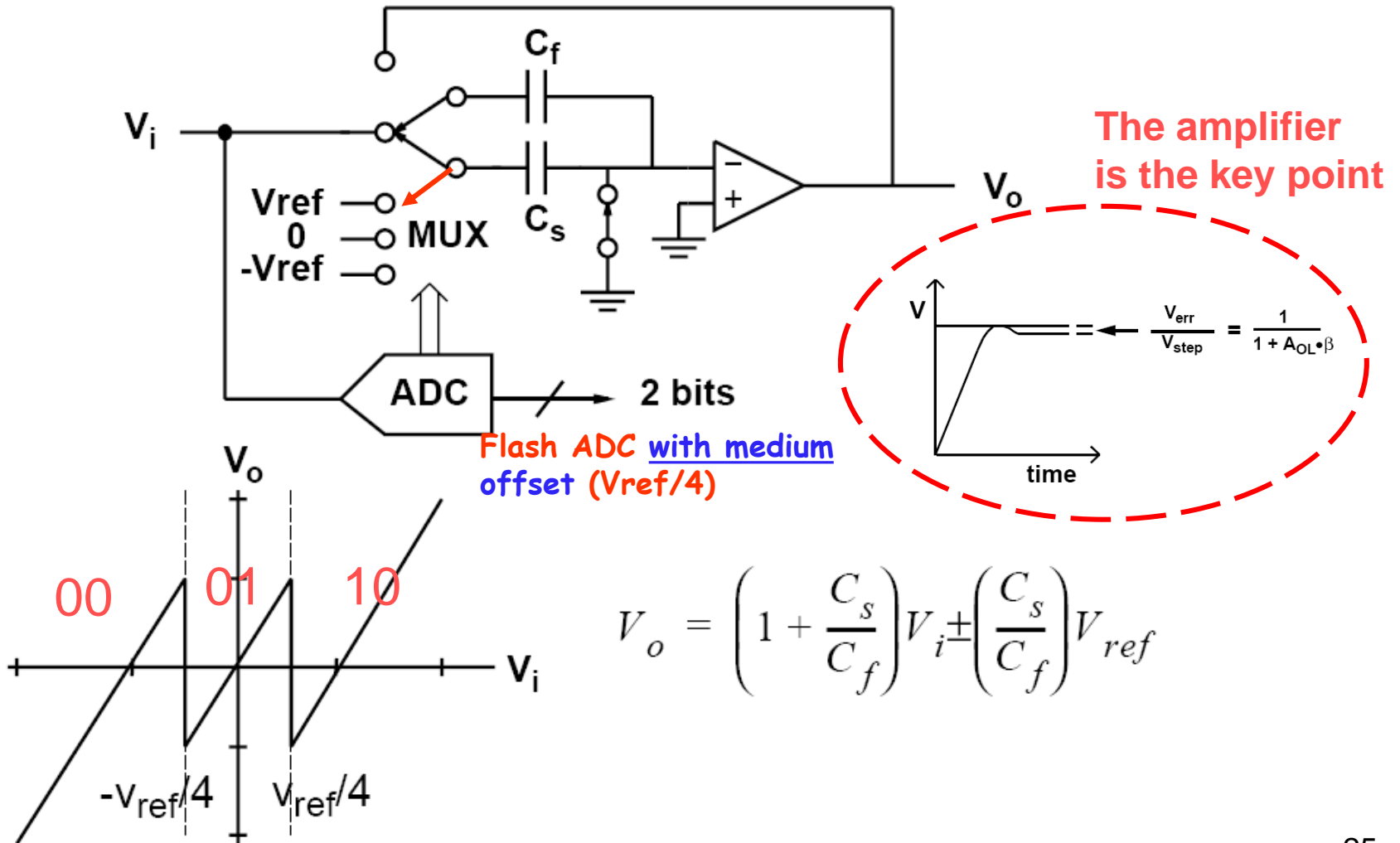
Very very critical

Low signal amplification
Offset compensation
CM control
Noise issue, distortion

.....



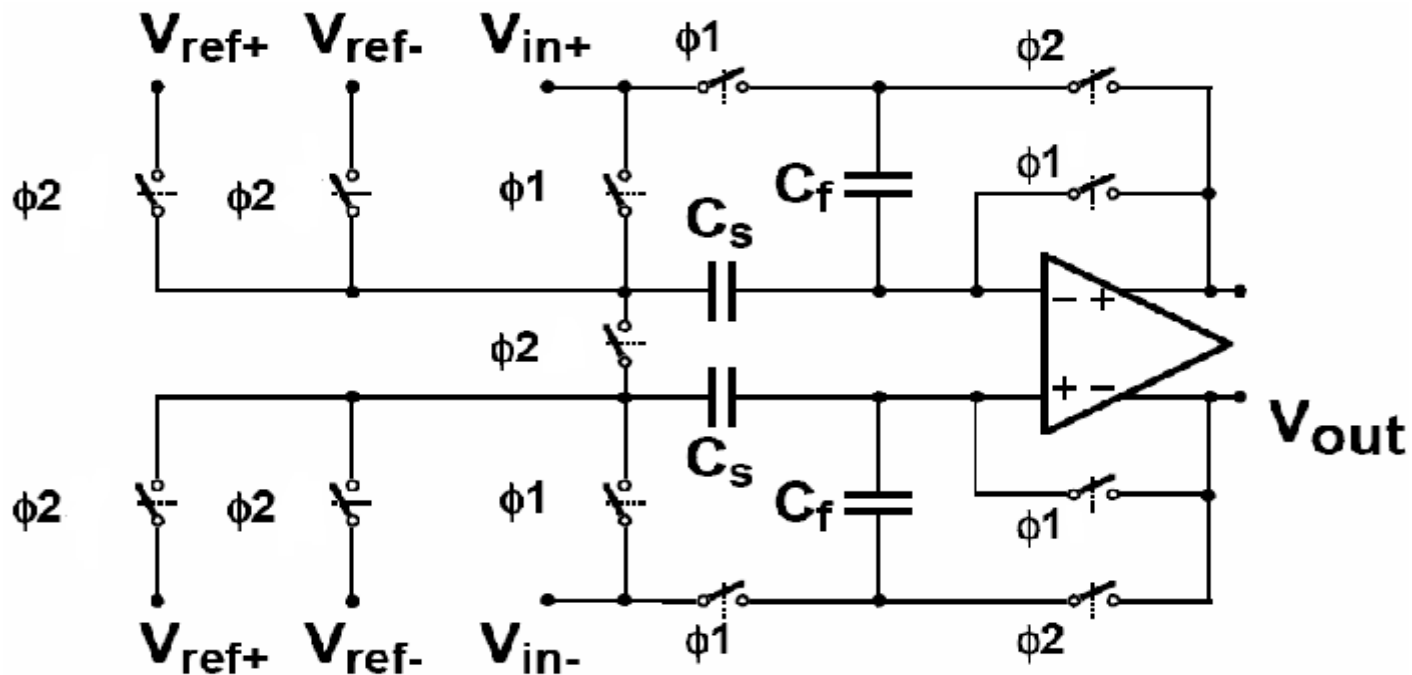
MDAC Function: Multiplier & DAC



$$V_o = \left(1 + \frac{C_s}{C_f}\right) V_i \pm \left(\frac{C_s}{C_f}\right) V_{ref}$$

Differential MDAC scheme

$$V_{out} = 2 * V_{in} \pm \alpha * V_{ref}; \text{ with } \alpha = \pm 1; 0$$



Pipeline ADC Model (1)

- 1.5 bit MDAC stage
- 2.5 bit MDAC stage

Error sources:

Switches linearity

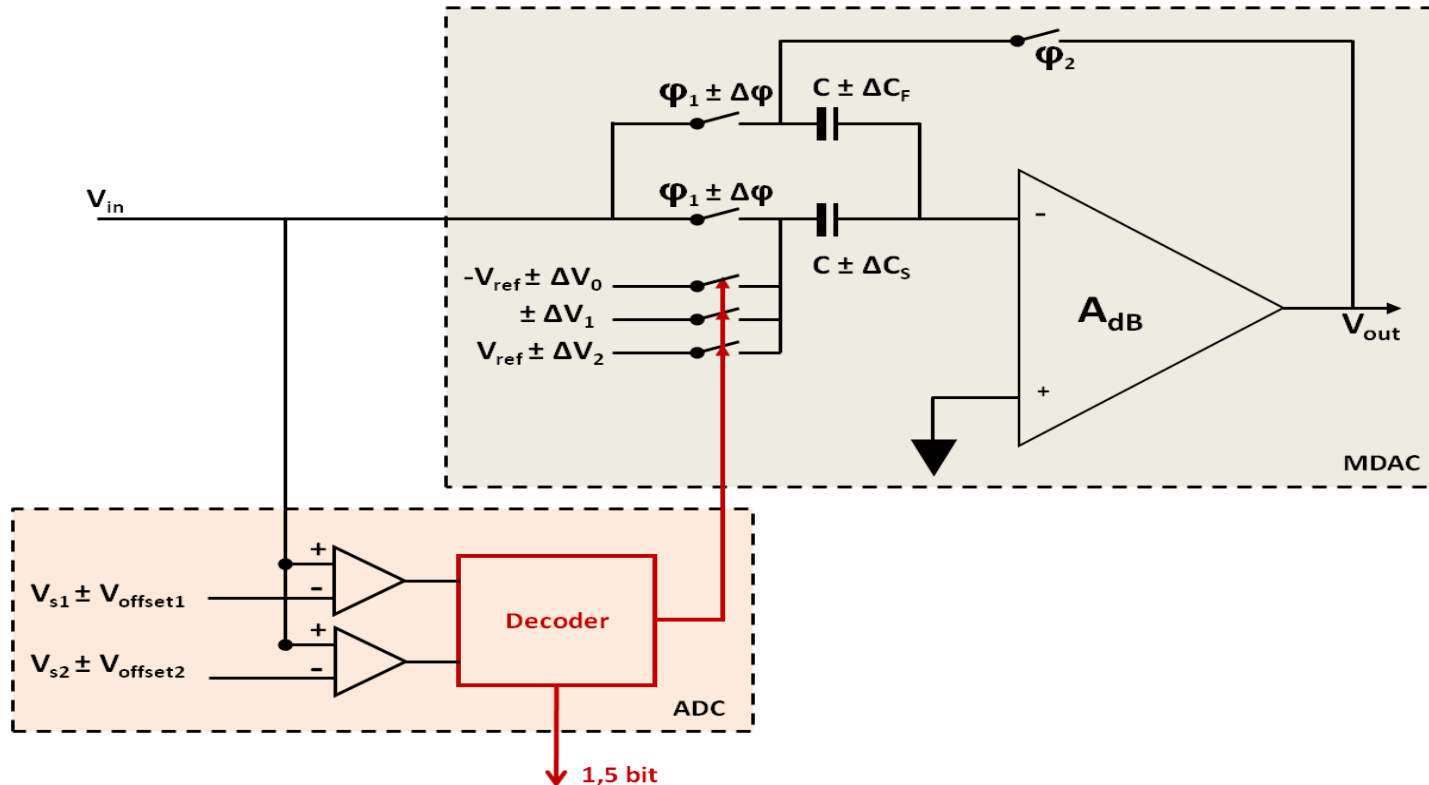
Clock distribution: (Sampling instant + Jitter)

Gain

OTA: A_{dB}

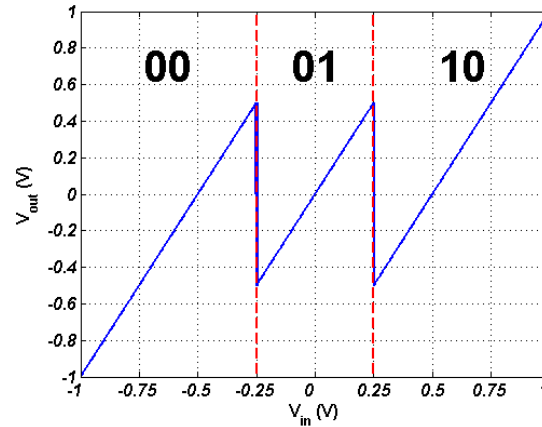
MDAC gain (capacitors)

Reference voltages ($\pm V_{ref}$): drift & noise



MDAC Transfer function

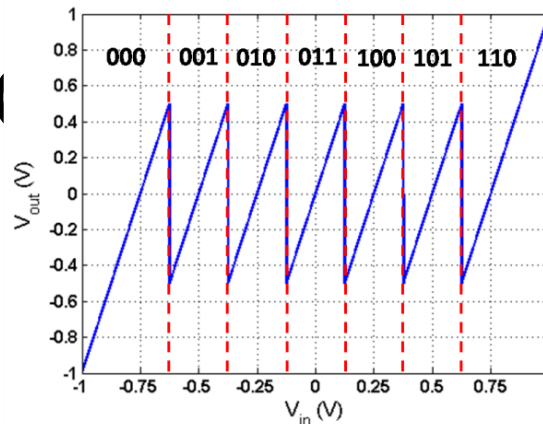
- 1.5 bit MDAC $V_{out} = 2 \cdot V_{in} - D_i \cdot V_{ref}$



$$D_i = [0, \pm 1]$$

$$V_{out} = 4 \cdot V_{in} - K_i \cdot V_{ref}$$

- 2.5 bit MDAC

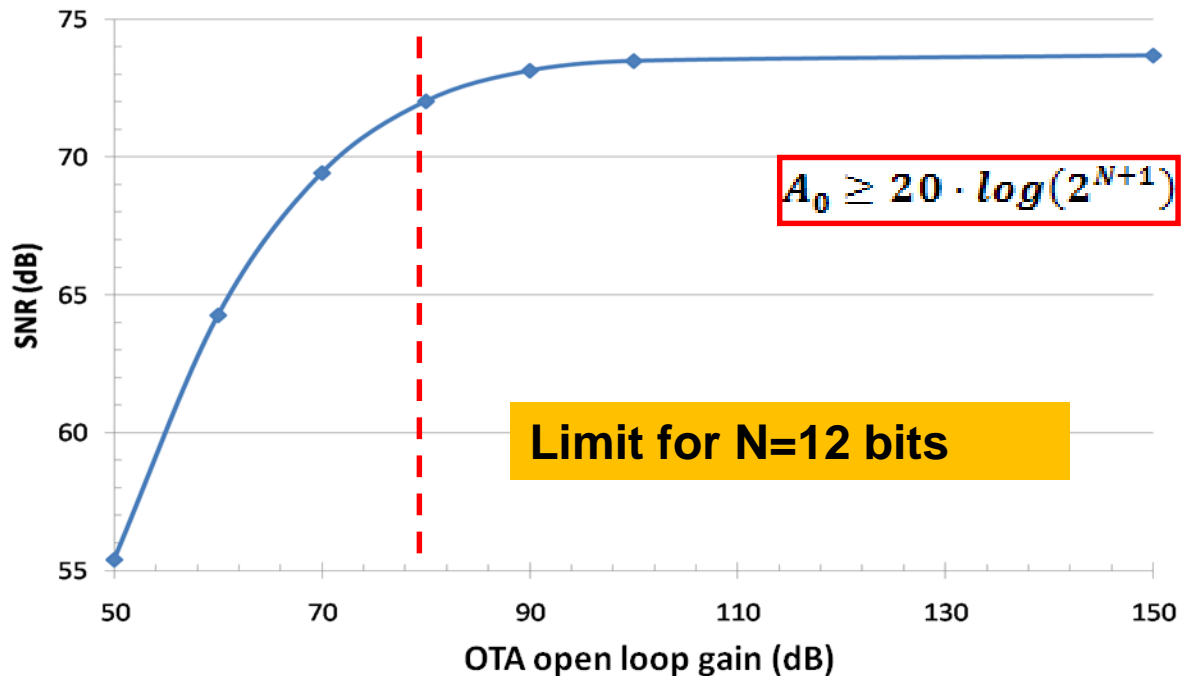


$$K_i = [0, \pm 1, \pm 2, \pm 3]$$

Pipelined ADC

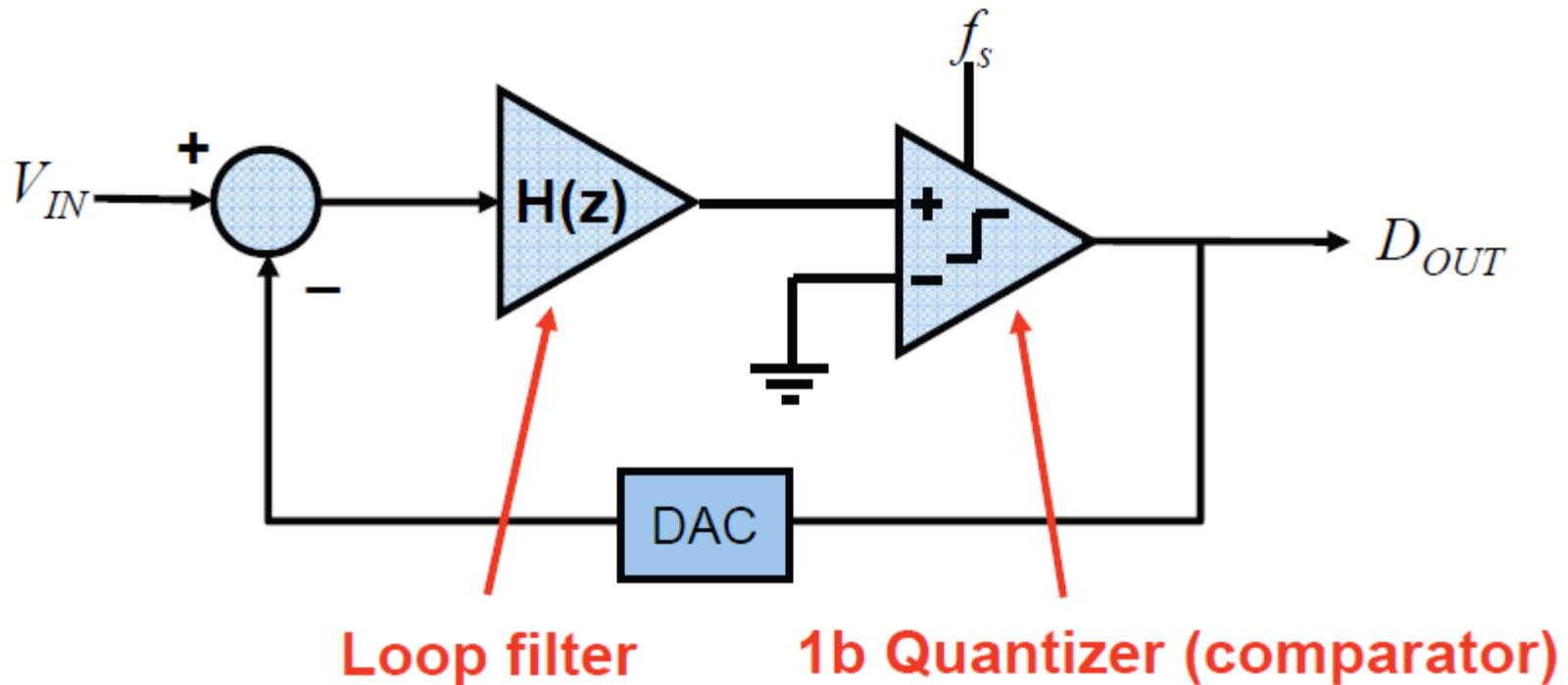
- OTA Open loop gain issues

$$V_{out} = (2 \cdot V_{in} - D_i \cdot V_{ref}) \cdot \frac{1}{1 + \frac{1}{A_0 \cdot F_{fb}}} \quad \text{with, } F_{fb} = \frac{C_f}{C_f + C_s + C_{in}}$$

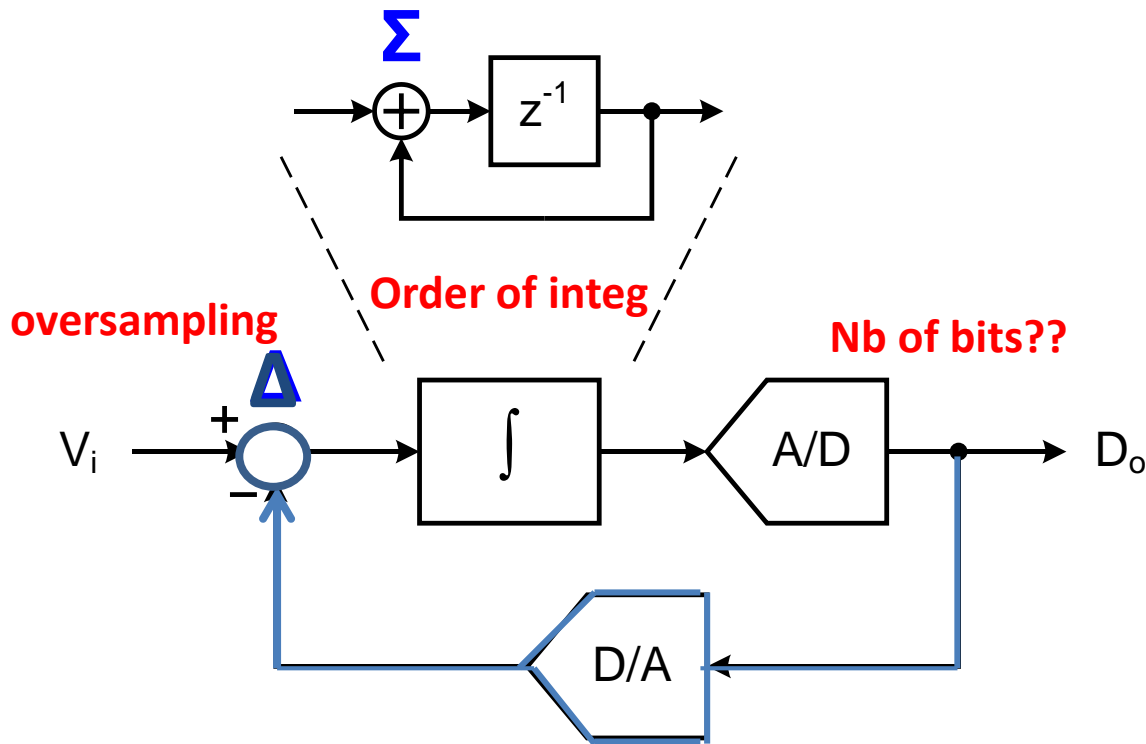


Oversampling ADC: Sigma delta modulator

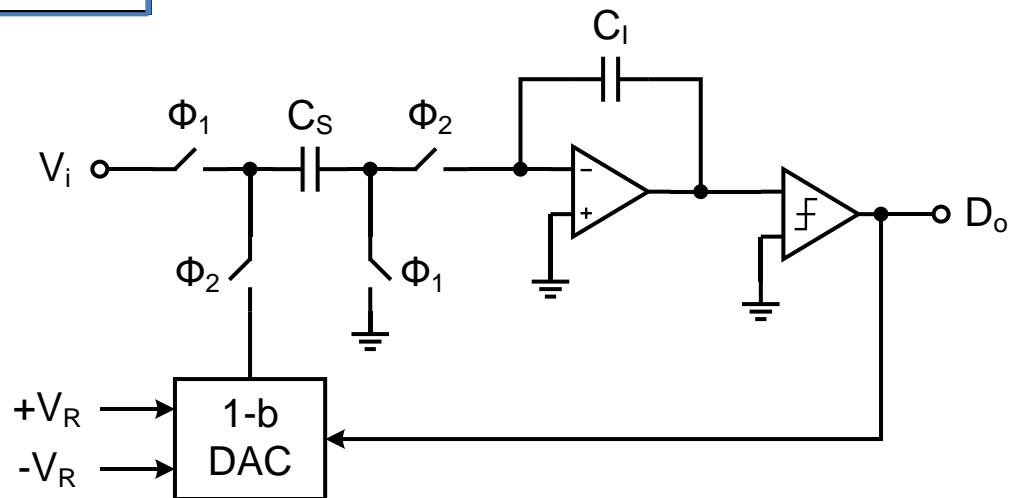
Analog 1-Bit $\Sigma\Delta$ modulators convert a continuous time analog input v_{IN} into a 1-Bit sequence D_{OUT}



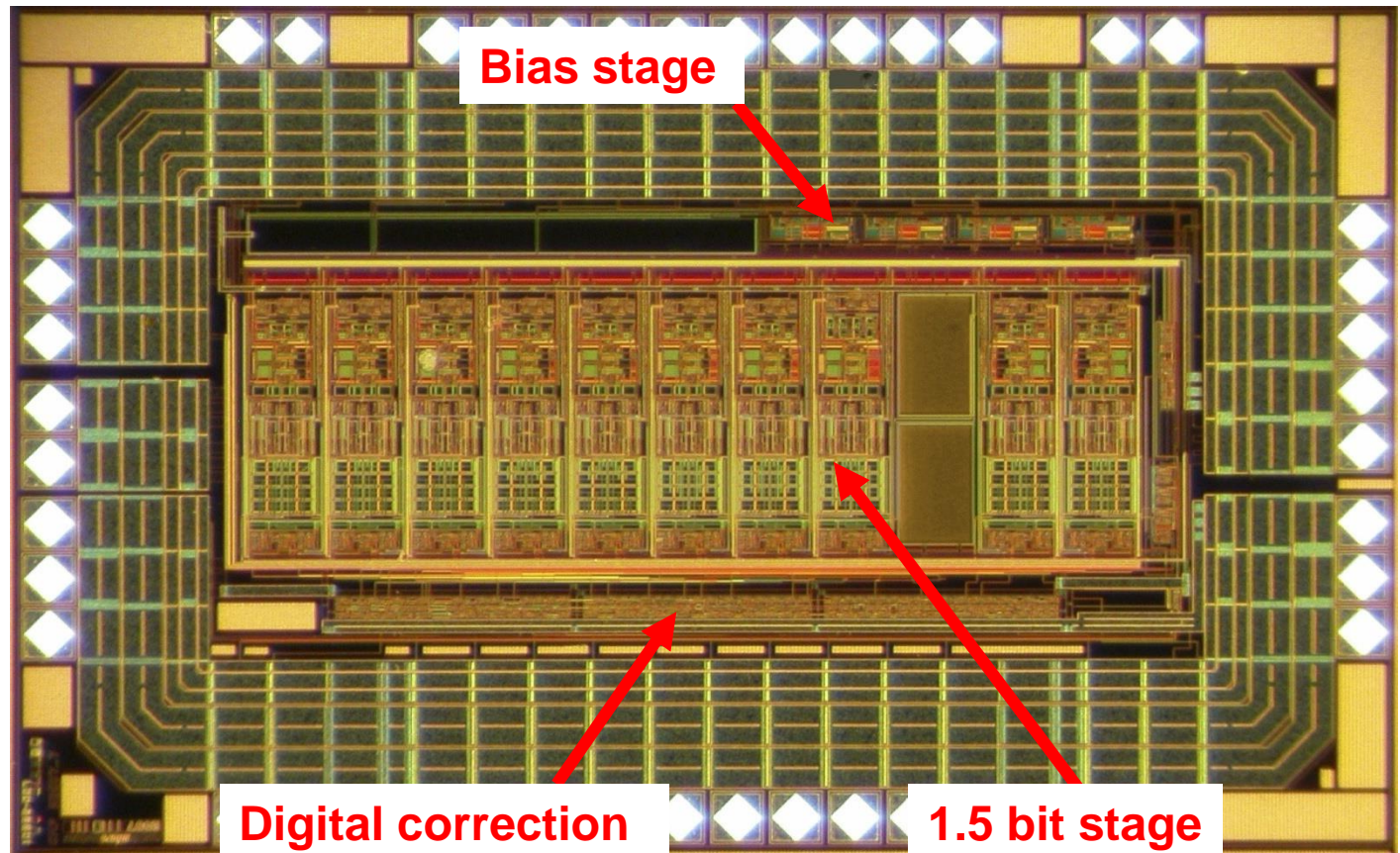
Sigma Delta Modulator



First order version of modulator =>



Die photograph: ADC chip

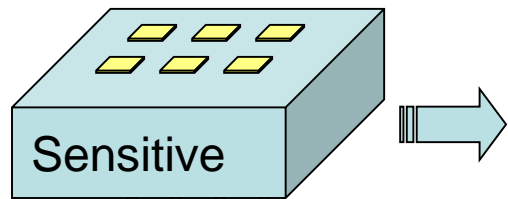


3D IT simplify view for SPECT-Xray CT

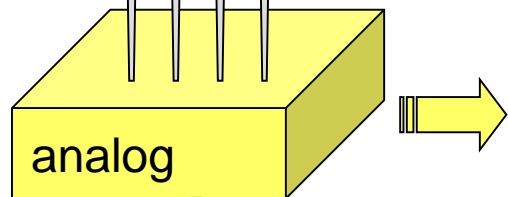
What we expect !

Large surface FOV=20x20 cm²

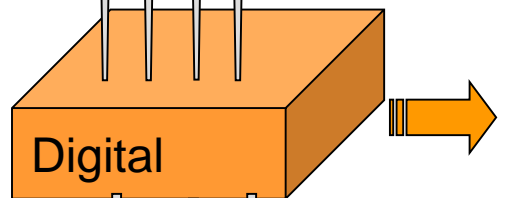
Megapixel Sensor



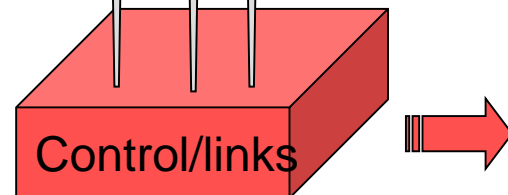
- ✓ Direct γ conversion CdZnTe/CdTe...
- ✓ 1-10 Megapixels – Pitch < 50 μm



- ✓ Amplifier
- ✓ Discriminator: two thresholds for “energy selection” or windowing for two simultaneous tracer imaging



- ✓ Fast readout-Photon counting strategy : $\sim 10^6$ ph/pixel/s for X-ray; Medipix or XPAD3 like architecture
- ✓ Time stamping



- ✓ Gating capability for X-ray and
- ✓ Fast readout for dynamical imaging (cardiac movements)

Thanks !!